

10th International Conference on Spectroscopic Ellipsometry

June 08-13, 2025, Boulder, Colorado, USA

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10th International Conference on Spectroscopic Ellipsometry

June 8–13, 2025, in Boulder, CO, USA

Program Schedule Overview

(June 11, 2025)

	Sunday June 8	Monday June 9	Tuesday June 10	Wednesday June 11	Thursday June 12	Friday June 13
		30+5*15=105min				
	CUB Memorial Center https://www.colorado.edu/umc/ Dated: 6-9-2025	Industrial Applications: Antonelli	Adv Instrum 2: Aspnes	THz Instruments & Appl: Podraza	ALD/in-situ/real-time: Espinoza	Semiconductors: Zapfen
	8:00	K 0014 Diebold (SUNY Albany)	V 208 Liu (Wuhan)	K 208 Darakchieva (Lund)	K 207 George (UC Boulder)	K 178 Zollner (NMSU)
	8:30	C 073 Furedi (Budapest)	C 157 Johns (Film Sense)	C 105 Mainali (Toledo)	C 072 Magnozzi (Genova)	C 043 Armenta (NMSU)
	8:45	C 124 Ghim (Daejeon, SK)	C 116 Tschammer (Cottbus)	C 154 Postava (Ostrava)	C 189 Traouli (Lincoln)	C 096 Love (NMSU)
	9:00	C 089 Hrabovsky (Praha)	V 166 Yang (Beijing)	C 181 Arbab (Stony Brook)	C 080 Cobet (U Linz Austria)	C 022 Gruembel (TU Magdeburg)
	9:15	C 066 An (Ansan, SK)	C 179 Fried (Budapest)	C 104 Ramanujam (Toldeo)	C 160 Junige (UC Boulder)	C 184 Sema Kilic (Lincoln)
	9:30	C 075 Marton (SemiLab Hungary)	C 118 Bian (Barcelona)	C 138 Armakavicius (Linköping)	C 156 Peiris (Kenyon College)	C 173 Nafisa (Kennesaw)
8:30	Registration 8am-5pm	9:45 30min break	30min break	30min break	30min break	30min break
9:45	Opening	20+6*15=110				15+15+25+15+15+15+10=110 min
	Tutorial 1: Chair: Jellison	Advcd Instrum. & Model: Kilic	Thin Films: Petric	Thin Films 2 & NanoSpec: Magnozzi	Low-D/Periodic: Serna	Award + ICSE-11: Schubert
10:00	T 165 Novikova	10:15 I 117 Yo (Samsung)	I 130 Rindert (Lund)	I 210 Bechtel (Berkeley)	V 137 Pierangelo (Paris)	C 301 Student awards 10
		C 115 Arteaga (Spain)	C 182 Stanishev (Lund)	C 078 Bisio (Genova, Italy)	C 051 Choi (Seoul)	C 302 Drude & Innovation awards 10
		10:50 C 106 Hong (JAWCo)	C 026 Tumenas (Vilnius)	C 037 Amonette (Toledo)	V 123 Zhang (Wuhan)	I 217 Synowicki (History) 30
	Tutorial 2	11:05 C 136 Soulan (Grenoble)	C 024 Lin (Osaka)	C 197 Puro (CU Boulder)	C 023 Cobelli (Padova)	I 303 Hans Mueller (Aspnes) 30
11:00	T 204 Podraza	11:20 C 003 Acher (Horiba)	25min break	C 139 Mascaretti (TU Prague)	C 070 Mistrik (Pardubice)	Q&A 10
		11:35 C 059 Kim (SKorea)		C 021 Hulagu (BAM)	C 110 Mukherjee (Budapest)	C 304 ICSE-11 10
		11:50 C 162 Zapfen (Hong Kong)	Bus UMC-Georgetown	C 063 Alaani	V 134 Furchner (HZB Berlin)	C 305 Closing 10
12:00	1h30min break	12:05 1h25min break		1h25min break	1h25min break	
		20+6*15=110				
	Tutorial 3: Schubert	Ultrafast SE: Zollner		Analysis: Arwin	Anisotropy: Armakavicius	T: 50+10min Tutorial
13:30	T 206 Kessels	13:30 I 140 Espinoza (ELI, Innv. Awardee)		K 053 Zheng (Fudan)	I 145 Sturm	K: 25+5 min Keynote
		13:50 C 108 Schmidt-Grund (TU Ilmenau)		ctnd	C 076 Jellison (ORNL)	I: 17+3min Invited
		14:05 C 056 Rebarz (Dolní Břežany)	14:00	I 203 Aspnes (NCSU)	C 149 Wilhelm (PNNL)	C: 12+3min Contributed
14:30	30min break	14:20 C 131 Gera (Szeged, Hungary)		C 087 Serna (Madrid)	C 122 Vegesna (Jena)	V: Video
		14:35 C 028 Baron (TU Magdeburg)		C 038 Sun (JAWCo)	C 006 Arwin (Linköping)	Student Presenter
		14:50 C 093 Armenta (NMSU)		C 064 Hettige (NMSU)	C 128 Duwe (Park Germany)	
	Tutorial 4: Diebold	15:05 C 126 Henn (Leipzig)		C 102 Kanneboina (Toledo)	C 017 Frye (Toledo)	
15:00	V 205 Urban	15:20 15min break		15min break	15min break	
		20+15+15+15=65		30+20+15=65		
		Imaging Ellipsometry: Fried		Workforce Development: Schmidt	EUV+nanosstructures: Fujiwara	
	Tutorial 5	15:35 I 098 Hingerl (Linz)		K 201 Antonelli (Onto)	I 216 Germer (NIST)	
16:00	T 191 Schubert	15:55 C 044 Okano (Park System Germany)		ctnd	C 186 Kamali Khanghah (Lincoln)	
		16:10 C 058 Hwang (Jeonbuk U SK)		16:05 V 202 Williams-Vaden (Semi F)	C 135 Martinez (NJIT)	
		16:25 C 004 Hulagu (BAM Berlin)	Bus Georgetown-UMC	C 045 Kim (Jeonbuk SK)	C 151 Plaickner (TU Berlin)	
17:00	30min break	16:40 15min break		15min break	15min break	
		20+15+15+15=65				
17:30	Bus UMC-Chatauqua	Chiral Properties: Arteaga		AI/ML: Sturm	Bio Applications: Isabel Alonso	
		16:55 I 187 Kilic (Lincoln, Drude Awardee)		I 012 Fujiwara (Gifu)	I 094 Petrik (Budapest)	
		17:15 C 013 Alonso (Barcelona)		C 011 Yamamoto (Gifu, Jap)	C 114 Agocs (Hannover)	
		17:30 C 042 McPeak (Louisiana SU)		V 099 Chen (Wuhan)	C 095 Labadi (Budapest)	
19:00	Reception Chatauqua	17:45 C 077 Jellison (ORNL)		C 036 Peters (Sentech)	C 083 Pardo (Barcelona)	
		18:00 10min break	Return to UMC	30min break	10min break	
		18:10 Poster Session 1		18:10 Poster Session 2		
22:00	Bus Chatauqua-UMC	20:00		18:30 Dinner	20:00	

Schedule of Events

Sunday, June 8 2025

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	<i>Chair: Alain Diebold</i>	
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08:00 - 08:30	Alain C. Diebold, Mueller Matrix Spectroscopic Ellipsometry based Scatterometry: Optical Dimensional and Shape Analysis	64
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